APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL Page 1											1	
E	SCC	Component	Title: C	MOS	S B, 4000	B Series	i			Appl. N	0.	
and a second		Executive M	lember: (CNES	6			D	ate: 19/03/202	73S		
Components (includin	ng series and families	s) submitted fo	or Extension	of Qu	alification	Approval:						1
ESCC COMPONENT NO.	IPON	IENTS	INTS BASED ON			TEST VEHICLE	COMPONEN SIMILAR	COMPONENT SIMILAR				
As per QPL									HCC4068BD	G A	As per QPL	
									HCC4011BK	т		
									НСС4093ВК	т		
									HCC4077BK HCC4014BD	-		
Component Ma STMicroelectronics		cation of Mar FRANCE	nufact	turing Plant	(s)	3	Date	of original qualifi : 01/04/ ficate Ref No.		val:	4	
ESCC Specifications Maintenance of qualit Generic: 9000 Detail(s): 9201/06 9201/043	used: No E	used: No ⊠ Yes □ (supply details in Box 15) Deviation from current Specifications:				Qualification Extension Report reference and date: HCC4068BDG ID 33807006ZW DC1909A HCC4011BKT ID 3314000EYD DC 1903A HCC4093BKT ID 33820008ZZ DC 1844A HCC4077BKG ID 330800302 DC1816A HCC4014BDK ID 3380700701 DC 1816A				7		
Summary of procurer	nont or oquivalant to	et roculte durir		lidity	poriod in su	innort of t	his an	plicatio	n (those to ESC)	C listed first)		8
Project Name	Testing Leve		LAT	inuity		Date code		plicatic		Quantity Del	livered	
Various	ESCC 9000 lss 10	sue			Lots deliv 2018 to D			ary	38 441			
PID changes since st	art of qualification		9	Cur	rrent PID \	/erified by	:		CNES			10
None 🗆								Name of Excutive Representative				
Minor*				Ref No: PID GENERIQI PID CMOS Ref				Ref. 8097046 re 37618 rev.11.0,				
Major* 🗆	*Provide details in b	ox:		Issu				.0 (CMOS) Date:			20/02/2018	
				Rev	/ Date: 3	31/01/202	0					11
Current Manufacturing facilities surveyed by:					CNES			or	ı	27-03-	-18	
			(Name	e of E	xecutive Re	presentat	ive)			(Da	te)	
Satisfactory: Report Reference:	Yes ⊠ <u>CR-ST-27-03-1</u>	No 8	Exp	olain								

	APPLICATI	ON FOR EXTENSIO	N OF ESCC QUALI	IFICATI	ON APPROVAL	Page 2
ESCC	Component title:	CMOS B, 4000B \$	Series			Appl. No.
	Executive Member:	CNES		Date:	19/03/2020	73S
Failure Analysis, DPA, NCCS ava	ailable: Yes	⊠ No □	(Supply data)			12
inside. No	001: HCC40103B lots explanation found for th inal transfer of CMOS ²	ne origin of the proble	em. HCC4013 now p			
The undersigned hereby certifies on behalt that the appropriate documentation has be (except as stated in box 15;) - that the repor CNES as the responsible Executive Mem	en evaluated; - that ful orts and data are availa	l compliance to all Es able at the ESCC Exe	SCC requirements is ecutive and therefore	evidence applies	on behalf of	13
Date: 25/03/2020				(Si	JP. BUSSEI	
Continuation of Boxes above:						14
[7] Qualification Extension report	s :					
The extension is based on collect	ion of 54HCMOS a	nd CMOS 4000B	data :			
AMK 4" and 5":						
AWK 4 and 5 . HCC4068BDG ID 33807006ZW DC1 HCC4011BKT ID 3314000EYD DC 1 HCC4093BKT ID 33820008ZZ DC 18 HCC4077BKG ID 330800302 DC181 AMK 6": HCC4014BDK ID 3380700701 DC 18	903A – ESCC9000 844A – ESCC9000 6A – ESCC9000 CI	chart F4 sg1-3 Chart F4 Sg2 nart F4 sg2				
Package qualification: Dual in Line: M54HC74DT – ID3374 (also available, HCC4068BDG – ID3 Flat pack: HCC4011BKT – ID331 (also available M54HC00KT – ID331 Cover the validation of packages for refers).	3807006ZW DC190 14000EYD DC1903 26D17YY DC1902	09A – ESCC 9000 A – ESCC 9000 c A – ESCC 9000 cl	chart F4 sg1-3) hart F4 sg1-3 hart F4 sg1-3)	its ma	rch 2001 meeting (minute 11.1
[9] Minor PID changes: - Wafer fab updated to AMK 6" for - Removal of products HCC4012B	-	1042B, HCC4082E	s (terminated pro	oducts)		

APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL Page 3								
Eve.	ESCC	Component	t title: CMOS B, 4000B Series			Appl. N	lo.	
	and the second s	Executive N	Nember: CNES	Date:	19/03/2020	73S	r	
Non compli	ance to ESCC requirements:						15	
No.:	Specification		Paragraph		Non compliance			
Additional t	asks required to achieve full co	mpliance for I	ESCC qualification or rationale for acceptability	/ of			16	
noncomplia	ance:							
Executive N	Manager Disposition						17	
Application		No 🗆						
Action / Re	marks:							
				51	Digitally signe by Britta Schar Date: 2020.04.	d de		
Date:				-1	Date: 2020.04. 09:44:47 +02'0	28		
					nade: Head of ESA Produ nd Safety Department	ct Assurance	е	

	APPLICATIO	PROVAL	Page 4			
ESCC	Component Title:	CMOS B, 4000B Series			Appl. No	D .
and a second	Executive Member:	CNES	Date:	19/03/2020	73S	
ANNEX 1: LIST OF TESTS DONE TO SUPF	PORT EXTENSION C	FQUALIFICATION				18
Tests conducted in compliance with:						
 ESCC 9000 generic specification Or PID-TFD 						
		Jans)				
Tests vehicle identification/description:						
AMK 4" and 5": HCC4068BDG ID33807006ZW DC19	0000					
HCC4011BKT ID3314000EYD DC 1						
HCC4093BKT ID33820008ZZ DC 18						
HCC4077BKG ID 330800302 DC181 AMK 6":	16A					
HCC4014BDK ID 3380700701 DC 1	816A					
Dual in Line :		e validation of packages for both				
M54HC74DT – ID33740004ZJ DC19 Flat-pack :		as agreed by Qualification Board arch 2001 meeting (minute 11.1				
HCC4011BKT ID 3314000EYD DC 1						
Detail Specification reference:						

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Chart F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Environmenta/Mechanical Subgroup	Mechanical Shock	X	MIL-STD-883, Test Method 2002		15	0	
	Vibration	\boxtimes	MIL-STD-883, Test Method 2007		15	0	
	Constant Acceleration	X	MIL-STD-883, Test Method 2001		15	0	
	Seal (Fine and Gross Leak)	\boxtimes	MIL-STD-883, Test Method 1014	Dual in Line : M54HC74DT –	15	15 0	
	Intermediate and End-Point Electrical Measurements	\boxtimes	Intermediate and End-Point Electrical Measurements in the Detail Specification	ID33740004ZJ DC1901A Flat-pack :	15	0	
	External Visual Inspection	X	ESCC Basic Specification No. 20500	HCC4011BKT ID3314000EYD DC 1903A	15	0	
ental/h	Thermal Shock	X	MIL-STD-883. Test Method 1011		15	0	
/ironm	Moisture Resistance	X	MIL-STD-883, Test Method 1004		15	0	
ĒD	Seal (Fine and Gross Leak)	X	MIL-STD-883, Test Method 1014		15	0	
	Intermediate and End-Point Electrical Measurements	X	Intermediate and End-Point Electrical Measurements in the Detail Specification		15	0	
	External Visual Inspection	X	ESCC Basic Specification No. 20500		15	0	

-	ESC	C	Component title:	CMOS B, 4000B Series				Page 5 Appl. No.
		Executive Member: CNES Date: 19/03/2020					03/2020	73S
Chart F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if no Comments or	ot performed. n Rejection
Endurance Subgroup	Operating Life		MIL-STD-883, Test Method 1005	AMK 4" and 5":	15	0		
	Intermediate and End-Point Electrical Measurements	×	Intermediate and End-Point Electrical Measurements in the Detail Specification	HCC4068BDG ID33807006ZW DC1909A HCC4011BKT ID3314000EYD DC	15	0		
	Seal (Fine and Gross Leak)		MIL-STD-883, Test Method 1014	1903A HCC4093BKT	15	0		
	External Visual Inspection		ESCC Basic Specification No. 20500	ID33820008ZZ DC 1844A HCC4077BKG ID330800302 DC1816A AMK 6": HCC4014BDK ID3380700701 DC 1816A	15	0		
dno	Permanence of Marking		ESCC Basic Specification No. 24800	Dual in Line : M54HC74DT – ID33740004ZJ			Not applicable	
Subgr	Terminal Strength		MIL-STD-883, Test Method 2004	DC1901A	5	0		
Assembly Capability Subgroup	Internal Visual Inspection		ESCC Basic Specification No. 20400	Flat-pack : HCC4011BKT	5	0		
bly C	Bond Strength		MIL-STD-883 Test Method 2011	ID3314000EYD DC 1903A	2	0		
Assem	Die Shear or Substrate Attach Strength		MIL-STD-883 Test Method 2019 or 2027		2	0		
nal s								
Additional Tests								
Ac								

						.		
	000	APPLICATIO	ON FOR EXTENSION OF	ESCC QUALIFICATI	ON APPROVAL	Page 7		
se L	SCC	Component title:	CMOS B, 4000B Series			Appl. No.		
		Executive Member:	CNES	Date:	19/03/2020	73S		
N	OTES ON THE COMPL	ETION OF THE APPL	ICATION FORM FOR ES	CC QUALIFICATION	EXTENSION APPROVA	L		
ENTRIES Form heading			as given in its detail specif per and its sequential suffix		f the series, family; - the Ex	kecutive Member;		
Box 1	shall provide details given in the table; in particular there shall be listed: - the variants or range of variants; - the range of components (the ESCC code is recommended to indicate the values or values range, the tolerance, the voltage, etc); the designation given in the detail specification as 'base on'; - under Test Vehicle enter either an ESCC code or the specific characteristic capable of identifying the component tested (e.g., voltage of coil for a relay); - under component similar enter a cross if relevant.							
Box 2; 3 and 4	As per QPL entry;	otherwise, an explana	tion of the changes must b	e supplied.				
Box 5			il specifications, including tions are different from the					
Box 6	deviations this must	st be listed in Box 15. I	ic and Detail Specification In case the referenced spe tes or not from such currer	cification in Box 5 hav				
Box 7	Must reference the	e report(s) supplied in a	support of the application.					
Box 8	Should provide the details of procurement to the full ESCC System, documentation of all of which should already have been delivered to the ESCC Executive under the terms of the relevant Generic Specification. An appropriate table has been drawn in this box.							
Box 9		If the PID evolved after the Original Qualification or after the last Extension of Qualification, adequate details of such evolution shall be provided together with the reasons for the changes. Major changes shall be clearly marked.						
Box 10			ate and actual date of ver uired date of extension.	ification. The date o	f verification of the current	nt PID should be		
Box 11	practices, procedu	This box can be completed only after a physical visit to the plant to confirm that no unexplained changes occurred and that the practices, procedures, material, etc. used in manufacturing the components are as described in the PID. This survey shall be carried out in accordance with the requirements of ESCC Basic Specification No. 20200 and its findings shall be recorded.						
Box 12		s) (NCCS) occurred du	ny Destructive Physical A uring the qualification valid					
Box 13	Enter only the nar Coordinator.	me of the Executive N	Member (i.e., CNES, DLR	ESTEC, etc.) and t	he signature of the respo	onsible Executive		
Box 14			and any of the boxes from into 14a, 14b, etc. if severa			nce the Box 14 in		
Box 15	Fill in Table as req	uested.						
Box 16			/ by the Executive Membe herein or the reason(s) to			ly to be accepted		
Box 17			s on the application itself, s all be entered clearly in Bo					
Box 18	Fill in Table as req	uested.						
Box 19	Confidential Detail	s of PID changes inclu	uding those of a confidentia	I nature, shall be pro	vided.			
Box 20		nce with reference to a lly numbered. If releva	specification(s) and paragent state 'None'.	aph(s). To simplify r	eference in Box 16 each	nonconformance		
Box 21			/ by the Executive Membe herein or the reason(s) to			ly to be accepted		
Box 22	Additional Comme	nts.						